



NORWEGIAN CHEMICAL SOCIETY

DIVISION ANALYTICAL SCIENCES

PROGRAM

FOR

THE 16th NORWEGIAN X-RAY CONFERENCE

13 – 15 SEPTEMBER 2010

Quality Hotel & Resort Kristiansand

Monday 13 September

1100 REGISTRATION

1200 LUNCH

Chairman: Torkild Eivindson

1300 Opening: Torkild Eivindson

1310 Maggi Loubser (Invited Speaker), PPC Cement, South Africa.
“Representative sampling and the errors introduced in sampling and sample preparation”

1355 Hege Zahl*, on behalf of Elkem Solar AS, Norway.
*Employee: Xstrata Nikkelverk AS, Vesterveien 31. Boks 604 N-4606 Kristiansand Norway.
“Quality control charting”

1430 Coffee and exhibition

1515 Rainer Schramm, FLUXANA GmbH & Co. KG. Germany.
“Analysis of ashes with XRF based on fused beads”

1535 Kohei Kansai, Rigaku Europe SE, Germany.
“X-ray fluorescence analysis of rocks by fusion method using a benchtop WD-XRF”

1550 Elke Thisted, Elkem Solar Research, Kristiansand, Norway.
“Aging of a Li₂B₄O₇-glass - 5 years of analysis”

1600 End

1630 Departure for a Boat-trip.
Buss outside Hotel entrance from 1615.
Good walking shoes and warm clothes for those who want to visit an island.
It is room on the boat to stay indoor if poor weather.

2100 Dinner, Quality Hotel

Tuesday 14 September

Chairman: Lorentz Petter Lossius

- 0900 Elke Schwöbel (Invited Speaker), Bruker AXS GmbH, Germany.
"Quantitative XRD-analysis of phases with known, partial or no known crystal structures"
- 0945 Jakob Noreland, XRF & XRD Regional Specialist, PANalytical B.V, Sweden.
"Using XRD in the hunt for cost and CO2 reductions in the metal and mining industry"
- 1015 Katarzyna Mirek-Sliwa(2), Darrell Harman(1), Lorentz Petter Lossius(2)
(1) Hydro Aluminium Kurri Kurri, Australia. (2) Hydro PMT Årdal, Norway.
"Advantages in use of the Multivariate Regression (MVR) method in the XRD bath acidity analysis"
- 1030 Coffee and exhibition
- 1100 Elke Thisted, Elkem Solar Research, Kristiansand, Norway.
"Routine XRD analysis on anode material - our experience –"
- 1110 Stein Rørvik, SINTEF, Norway.
"A review of problems related to Lc measurements by XRD of carbon materials"
- 1125 Egorov V.K., Egorov E.V. Institute of microelectronics technology Russian academy of science, Moscow, Russia.
"Waveguide-resonance propagation mechanism for X-ray flux and its realization conditions"
- 1155 Lunch

Chairman: Helene Trøite

- 1300 Renaat van Geel* & D. Bonvin, Thermo Fisher Scientific, Ecublens, Switzerland,
*Thermo Fisher Scientific, Breda, NL
"Concept differences in an XRF goniometer system"
- 1330 Akihiko Iwata, Rigaku Europe SE, Germany.
"Development of a high brilliance rotating anode dual-wavelength X-ray generator and multi-layer mirror for dual-wavelength"
- 1345 Lorentz Petter Lossius, Hydro Aluminium, Årdalstangen, Norway.
"XRF of Aluminium Fluoride – Interlaboratory Study for ISO Precision"
- 1415 Coffee and exhibition
- 1500 Hege Indresand, Postdoctoral Scholar, IMPROVE Program, Crocker Nuclear Laboratory,
University of California Davis
"Advanced Reference Materials for XRF Analysis in the US IMPROVE Atmospheric Particulate Matter Network"
- 1530 M.Haschke, U.Rosseck, R.Tagle, U.Waldschläger and H. Wagenknecht, Bruker Nano GmbH, Berlin, Germany.
"Ultra-fast and sensitive element distribution measurement using μ -XRF"
- 1600 Torfinn Fongen, Holger Teknologi AS, Oslo, Norway
"Uses for portable XRF"
- 1645 End
- 1930 Banquet

Wednesday 15 September

Chairman: Irene Solås

- 0900 Kevin Young (Invited Speaker), Peter Sheppardson, Sibelco Europe, England.
“Practical Aspects of the X-ray Characterisation of Silicate and Alumino-silicate Industrial Minerals”
- 0945 P. Lemberge¹, Renaat van Geel¹, F. Herzog² and M.S. Krzemnicki²
¹ ThermoFisher Scientific, Ecublens, Switzerland.
² Swiss Gemmological Institute SSEF, Basel, Switzerland.
“ED-XRF analysis to determine the origin and authenticity of gemstones”
- 1015 Coffee and exhibition
- 1030 Armand Jonkers, Application specialist XRF, PANalytical, Almelo, The Netherlands.
“Advances in standardless analysis”
- 1100 Ingvar Bernhardsson, D-LAB, Degerfors, Sweden.
”Multi base, multi range calibration”
- 1120 Dirk Wissmann, SPECTRO Analytical Instruments GmbH, Kleve, Germany.
“XRF - Calculation of results - empirical, semi-empirical, fundamental parameters - versatility vs. precision vs. accuracy”
- 1150 Conference closing
- 1300 Lunch